Search Notes



Application/Control No.	Ap Re
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Applicant(s)/Patent under Reexamination
BEYER ET AL.

10/520,885 Examiner

HIEU T. VO

Art Unit

3747

	SEAR	CHED	
Class	Subclass	Date	Examiner
101	114 112 102 115 99	3/6/2006	VH
123	478 479 494	3/6/2006	VH
73	117.3 116	3/6/2006	VH
73	118.1	3/6/2006	VH
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
EAST		3/6/2006	VH